



12500 TI Boulevard, MS 8640, Dallas, Texas 75243

**PCN# 20130422001
Add Cu Wire as Alternative Wire Base Metal for
Select QFN Package Devices
Change Notification / Sample Request**

Date: 4/25/2013
To: MOUSER PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 90 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN_admin_team@list.ti.com).

Sincerely,

PCN Team
SC Business Services
Phone: +1(214) 480-6037
Fax: +1(214) 480-6659

20130422001
Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
CC2530F128RHAT	null
CC2530F256RHAT	null
CC2530F32RHAT	null
CC2530F64RHAT	null
CC2531F256RHAR	null
CC2531F256RHAT	null
CC2540F128RHAT	null
CC2540F256RHAT	null
CC2541F128RHAT	null
CC2541F256RHAT	null
CC2570RHAT	null
CC2571RHAT	null

Technical details of this Product Change follow on the next page(s).

PCN Number:	20130422001			PCN Date:	04/25/2013						
Title:	Add Cu Wire as Alternative Wire Base Metal for Select QFN Package Devices										
Customer Contact:	PCN Manager	Phone:	+1(214)480-6037		Dept: Quality Services						
Proposed 1st Ship Date:	07/25/2013		Estimated Sample Availability:	Date provided at sample request.							
Change Type:											
☐	Assembly Site	☐	Assembly Process	☒	Assembly Materials						
PCN Details											
Description of Change:											
Texas Instruments is pleased to announce the qualification of Cu as an additional bond wire option for devices listed in "Product affected" section below. Devices will remain in current assembly facility and Material differences are shown in the following table: <table border="1"> <tr> <td>Material Set</td> <td>Current Assembly Au wire</td> <td>Cu Bond wire option</td> </tr> <tr> <td>Wire diam (Mils)</td> <td>0.96</td> <td>0.80</td> </tr> </table>						Material Set	Current Assembly Au wire	Cu Bond wire option	Wire diam (Mils)	0.96	0.80
Material Set	Current Assembly Au wire	Cu Bond wire option									
Wire diam (Mils)	0.96	0.80									
Reason for Change:											
Continuity of supply. 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties 2) Maximize flexibility within our Assembly/Test production sites. 3) Cu is easier to obtain and stock											
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):											
None.											
Changes to product identification resulting from this PCN:											
None.											

Product Affected:				
CC1101-LP-RGPR	CC2530F12CRHAR	CC2533F96RHAR	CC2570RHAR	
CC1101RGP	CC2530F256RHAR	CC2533F96RHAT	CC2570RHAT	
CC1101RGPR	CC2530F256RHAT	CC2534RHAR	CC2571RHAR	
CC1101RGPT	CC2530F25CRHAR	CC2534RHAT	CC2571RHAT	
CC110LRGPR	CC2530F32RHAR	CC2534RHAX	FRE006RHBR	
CC110LRGPT	CC2530F32RHAT	CC2540F128RHAR	FRE006RHBT	
CC1110F16RHHR	CC2530F64RHAR	CC2540F128RHAT	FRE008RHAR	
CC1110F16RHHT	CC2530F64RHAT	CC2540F256RHAR	FRE009RHAR	
CC1110F32RHHR	CC2531F128RHAR	CC2540F256RHAT	FRE010RHAR	
CC1110F32RHHT	CC2531F128RHAT	CC2541F128RHAR	HPA00700F256RHAR	
CC1110F8RHHR	CC2531F256RHAR	CC2541F128RHAT	HPA00702F128RHAR	
CC1110F8RHHT	CC2531F256RHAT	CC2541F256RHAR	HPA00703F64RHAR	
CC113LRGPR	CC2533ARHAR	CC2541F256RHAT	HPA01064RHAR	
CC113LRGPT	CC2533F32RHAR	CC2541SRHAR	HPA01215RHAR	
CC115LRGPR	CC2533F32RHAT	CC2541SRHAT	HPA01216RHAR	
CC115LRGPT	CC2533F64RHAR	CC2544RHB	HPA02146RHAR	
CC2530F128RHAR	CC2533F64RHAT	CC2544RHBR	TLMW301RGPR	
CC2530F128RHAT	CC2533F96RHA	CC2544RHBT	CC2540F25ARHAR	

Qualification Plan				
This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.				
Qual Vehicle 1 : CC2533RHA (MSL 3-260C)				
Package Construction Details				
Qualification Schedule:	Start:	Mar 2013	End:	Jun 2013
Assembly Site:	TI Clark	Mold Compound:		4208625
# Pins-Designator, Family:	40-RHA, QFN	Mount Compound:		4207123
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:		0.8 Mil Dia., Cu
Qualification:	☒ Plan ☐ Test Results			
Reliability Test	Conditions	Sample Size/Acc.		
		Lot#1	Lot#2	Lot#3
ESD HBM	+/- 1000V	3/0	3/0	3/0
ESD CDM	+/- 250V	3/0	3/0	3/0
Electrical Characterization	-40/+125C	30/0	30/0	30/0
Latch-Up	+90C	6/0	6/0	6/0
**T/C -55C/125C	-55C/+125C (700 Cyc)	77/0	77/0	77/0
**T/C -65C/150C	-65C/+150C (700 Cyc)	26/0	26/0	25/0
**High Temp. Storage Bake	150C (600 Hrs)	77/0	77/0	77/0
**Biased Temp. & Humidity	85C/85%RH (600 Hrs)	26/0	26/0	25/0
**Unbiased HAST	110C/85%RH/33.3 psia (264 Hrs)	77/0	77/0	77/0
Operating Life Test	125C (1000 Hrs)	39/0	39/0	38/0
Manufacturability (Assembly)	(per mfg. Site specification)	1/0	1/0	1/0
Notes ** - Preconditioning sequence: Level 3-260C.				

Qual Vehicle 2 : CC1101RGP (MSL 3-260C)					
Package Construction Details					
Assembly Site:	TI Clark	Mold Compound:	4208625		
# Pins-Designator, Family:	20-RGP, QFN	Mount Compound:	4207123		
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.8 Mil Dia., Cu		
Qualification:	☒ Plan	☐ Test Results			
Reliability Test	Conditions	Sample Size/Acc.			
		Lot#1	Lot#2	Lot#3	
ESD HBM	+/- 1000V	3/0	3/0	3/0	
ESD CDM	+/- 250V	3/0	3/0	3/0	
Electrical Characterization	-40/+85C	30/0	30/0	30/0	
Latch-Up	+90C	6/0	6/0	6/0	
**T/C -55C/125C	-55C/+125C (500 Cyc)	77/0	77/0	77/0	
**High Temp. Storage Bake	150C (600 Hrs)	77/0	77/0	77/0	
**Biased Temp. & Humidity	85C/85%RH (600 Hrs)	26/0	26/0	25/0	
**Unbiased HAST	110C/85%RH/33.3 psia (264 Hrs)	77/0	77/0	77/0	
Manufacturability (Assembly)	(per mfg. Site specification)	1/0	1/0	1/0	
Notes ** - Preconditioning sequence: Level 3-260C.					

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com